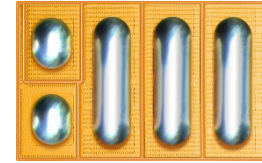


# EPC2014C\_55 – Enhancement-Mode Power Transistor Preliminary Specification Sheet

## Features:

- $V_{DS}$ , 40 V
- Maximum  $R_{DS(on)}$ , 16 m $\Omega$
- $I_D$ , 10 A



EPC2014C\_55 eGaN® FETs are supplied in passivated die form with solder bars.

**Die Size: 1.7 mm x 1.1 mm**

Maximum Ratings			
$V_{DS}$	Drain-to-Source Voltage (Continuous)	40	V
	Drain-to-Source Voltage (up to 10,000 5ms pulses at 150°C)	48	
$I_D$	Continuous ( $T_A = 25^\circ\text{C}$ , $R_{\theta JA} = 43^\circ\text{C/W}$ )	10	A
	Pulsed ( $25^\circ\text{C}$ , $T_{PULSE} = 300 \mu\text{s}$ )	60	
$V_{GS}$	Gate-to-Source Voltage	6	V
	Gate-to-Source Voltage	-4	
$T_J$	Operating Temperature	-40 to 150	$^\circ\text{C}$
$T_{STG}$	Storage Temperature	-40 to 150	

Static Characteristics ( $T_J = 25^\circ\text{C}$ unless otherwise stated)							
PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT		
$BV_{DSS}$	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V}$ , $I_D = 125 \mu\text{A}$		40		V	
$I_{DSS}$	Drain Source Leakage	$V_{DS} = 32 \text{ V}$ , $V_{GS} = 0 \text{ V}$ , $T_J = 25^\circ\text{C}$			50	100	$\mu\text{A}$
		$V_{DS} = 32 \text{ V}$ , $V_{GS} = 0 \text{ V}$ , $T_J = -55^\circ\text{C}$			4	100	$\mu\text{A}$
$I_{GSS}$	Gate-to-Source Forward Leakage	$V_{GS} = 5 \text{ V}$ , $T_J = 25^\circ\text{C}$			0.4	2	mA
		$V_{GS} = 5 \text{ V}$ , $T_J = -55^\circ\text{C}$			0.04	2	mA
	Gate-to-Source Reverse Leakage	$V_{GS} = -4 \text{ V}$ , $T_J = 25^\circ\text{C}$			0.1	0.25	mA
		$V_{GS} = -4 \text{ V}$ , $T_J = -55^\circ\text{C}$			0.004	0.25	mA
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 2 \text{ mA}$ , $T_J = 25^\circ\text{C}$		0.8	1.4	2.5	V
		$V_{DS} = V_{GS}$ , $I_D = 2 \text{ mA}$ , $T_J = -55^\circ\text{C}$		0.8	1.6	2.5	V
$R_{DS(on)}$	Drain-Source On Resistance	$V_{GS} = 5 \text{ V}$ , $I_D = 25 \text{ A}$ , $T_J = 25^\circ\text{C}$			12	16	m $\Omega$
		$V_{GS} = 5 \text{ V}$ , $I_D = 25 \text{ A}$ , $T_J = -55^\circ\text{C}$			8	11.5	m $\Omega$

All measurements were done with substrate shorted to source.

Thermal Characteristics			
		TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction to Case	3.6	$^\circ\text{C/W}$
$R_{\theta JB}$	Thermal Resistance, Junction to Board	9.3	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1)	80	$^\circ\text{C/W}$

Note 1:  $R_{\theta JA}$  is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See [http://epc-co.com/epc/documents/product-training/Appnote\\_Thermal\\_Performance\\_of\\_eGaN\\_FETs.pdf](http://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf) for details.

# EPC2014C\_55 – Enhancement-Mode Power Transistor

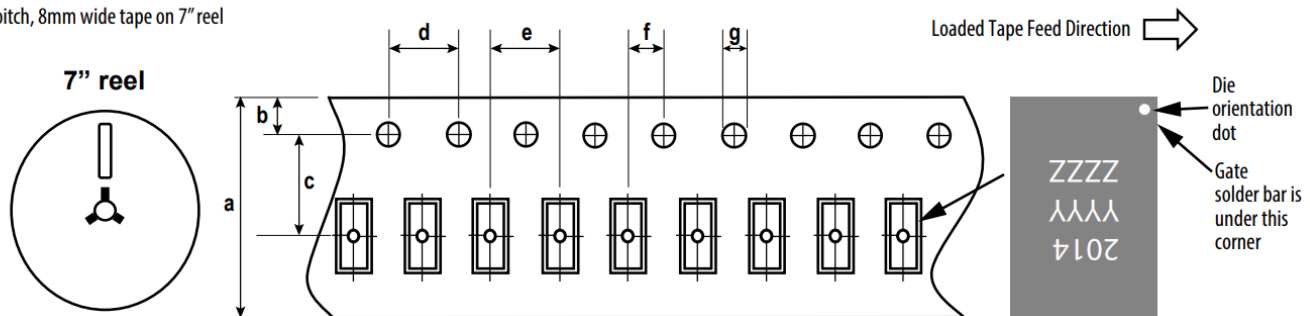
## Preliminary Specification Sheet

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$C_{ISS}$	Input Capacitance	$V_{DS} = 20\text{ V}, V_{GS} = 0\text{ V}$		220	30	pF
$C_{RSS}$	Reverse Transfer			6.5	9.5	
$C_{OSS}$	Output Capacitance			150	21	
$R_G$	Gate Resistance			0.4		$\Omega$
$Q_G$	Total Gate Charge	$V_{DS} = 20\text{ V}, V_{GS} = 5\text{ V}, I_D = 10\text{ A}$		2	2.5	nC
$Q_{GS}$	Gate-to-Source Charge	$V_{DS} = 20\text{ V}, I_D = 10\text{ A}$		0.7		
$Q_{GD}$	Gate-to-Drain Charge			0.3	0.5	
$Q_{G(TH)}$	Gate Charge at Threshold			0.5		
$Q_{OSS}$	Output Charge	$V_{DS} = 20\text{ V}, V_{GS} = 0\text{ V}$		4	6	
$Q_{RR}$	Source-Drain Recovery			0		

All measurements were done with substrate shorted to source.

### TAPE AND REEL CONFIGURATION

4mm pitch, 8mm wide tape on 7" reel

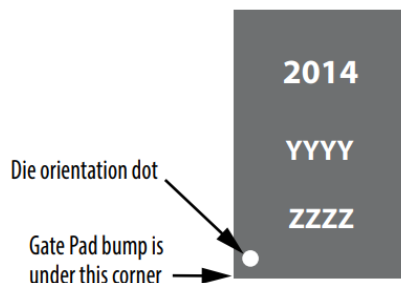


Die is placed into pocket solder bar side down (face side down)

Dimension (mm)	EPC2014C (note 1)		
	target	min	max
a	8.00	7.90	8.30
b	1.75	1.65	1.85
c (note 2)	3.50	3.45	3.55
d	4.00	3.90	4.10
e	4.00	3.90	4.10
f (note 2)	2.00	1.95	2.05
g	1.5	1.5	1.6

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/JEDEC industry standard.  
 Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

### DIE MARKINGS



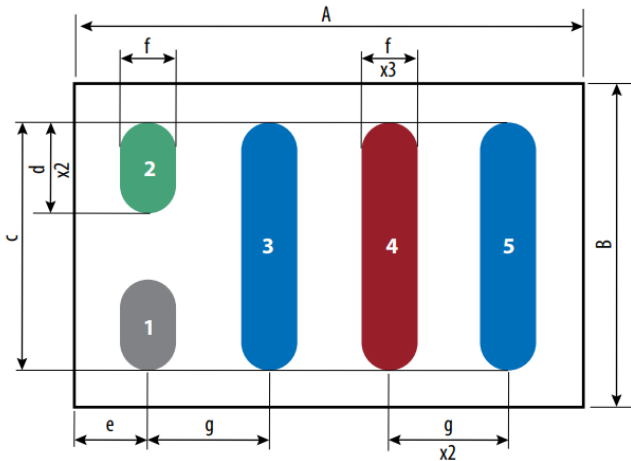
Part Number	Laser Markings		
	Part # Marking Line 1	Lot_Date Code Marking line 2	Lot_Date Code Marking Line 3
EPC2014C	2014	YYYY	ZZZZ

# EPC2014C\_55 – Enhancement-Mode Power Transistor

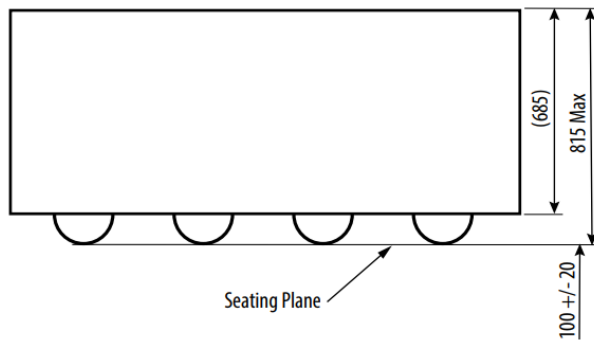
## Preliminary Specification Sheet

### DIE OUTLINE

Solder Bar View



### Side View

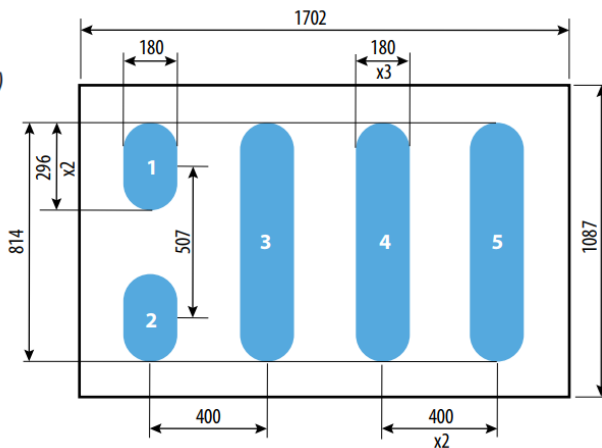


DIM	MICROMETERS		
	MIN	Nominal	MAX
A	1672	1702	1732
B	1057	1087	1117
c	829	834	839
d	311	316	321
e	235	250	265
f	195	200	205
g	400	400	400

Pad no. 1 is Gate;  
 Pad no. 2 is Substrate;  
 Pads no. 3 and 5 are Drain;  
 Pad no. 4 is Source

### RECOMMENDED LAND PATTERN

(measurements in  $\mu\text{m}$ )

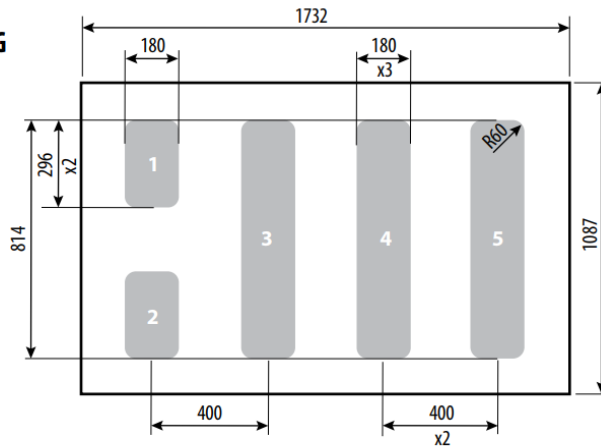


The land pattern is solder mask defined  
 Solder mask is 10  $\mu\text{m}$  smaller per side than bump

Pad no. 1 is Gate  
 Pad no. 2 is Substrate  
 Pads no. 3 and 5 are Drain  
 Pad no. 4 is Source

# EPC2014C\_55 – Enhancement-Mode Power Transistor Preliminary Specification Sheet

**RECOMMENDED  
STENCIL DRAWING**  
(units in  $\mu\text{m}$ )



Recommended stencil should be 4 mil (100  $\mu\text{m}$ ) thick, must be laser cut, opening per drawing. The corner has a radius of R60.

Intended for use with SAC305 Type 3 solder, reference 88.5% metals content.

Additional assembly resources available at  
<http://epc-co.com/epc/DesignSupport/AssemblyBasics.aspx>

Efficient Power Conversion Corporation (EPC) reserves the right to make changes without further notice to any products herein to improve reliability, function or design. EPC does not assume any liability arising out of the application or use of any product or circuit described herein; neither does it convey any license under its patent rights, nor the rights of others.

eGaN<sup>®</sup> is a registered trademark of Efficient Power Conversion Corporation.

EPC Patents: <http://epc-co.com/epc/AboutEPC/Patents.aspx>

Revised January, 2019